

**FORM PTO-1449
INFORMATION DISCLOSURE
STATEMENT BY APPLICANT(S)**

Atty Docket No. : 29287/137
Serial No. :
Inventors : HANZAWA, et al.
Filed : 25 June 2003
Group Art Unit : 2818
Examiner : Viet Q. Nguyen

U.S. PATENT DOCUMENTS

Examiner Initial	Patent Number	Patent Date	Name	Class/ Subclass	Filing Date
<u>UN</u>	6,452,858	09-2002	HANZAWA, et al.	365/230.06	
<u>UN</u>	6,545,897	04-2003	FUJISAWA, et al.	365/230.08	
<u>UN</u>	6,545,525	04-2003	ITOH, et al	327/524	
<u>UN</u>	2001/0028581	10-2001	YANAGISAWA, et al	365/189.05	
<u>UN</u>	2001/0009519	07-2001	FUJISAWA et al.	365/51	
<u>UN</u>	2001/0001598	05-2001	NARUI, et al.	365/149	
<u>UN</u>	6,535,435	03-2003	TANAKA, et al.	365/189.09	
<u>UN</u>	6,501,672	12-2002	SEKIGUCHI, et al.	365/72	
<u>UN</u>	6,480,425	11-2002	YANAGISAWA, et al	365/189.05	
<u>UN</u>	6,452,858	09-2002	HANZAWA, et al.	365/230.06	

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class/ Subclass	Translation Yes No

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner
Initial

**VIET Q. NGUYEN
PRIMARY EXAMINER**

EXAMINER

DATE CONSIDERED

V. Nguyen

8/24/07

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

INFORMATION DISCLOSURE STATEMENT BY APPLICANT PTO FORM 1449	ATTY. DOCKET NO. 29287/137	SERIAL NO. (Con.. of 10/201,317)
	APPLICANT HANZAWA et al.	
	FILING DATE Viet D. Nguyen (Anticipated)	GROUP 2018 (Anticipated)

U. S. PATENT DOCUMENTS

EXAMINER INITIAL	PATENT NUMBER	PATENT DATE	NAME	CLASS	SUBCLASS	FILING DATE
IN	2002/0041531 A1	04/11/02	TANAKA et al.	365	205	

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
W	JP 02001195879A	07/01	Japan				
W	JP 407057461 A	03/95	Japan				

**VIET Q. NGUYEN
OTHER DOCUMENTS PRIMARY EXAMINER**

EXAMINER INITIAL	AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.
W	IEEE International Solid-State Circuits Conference, Digest of Technical Papers, 1972, pp. 10-11.*
W	IEE Electronics Letters, May 13, 1999, Vol. 35, No. 10, pp. 848-850.*
W	European Solid-State Circuits Conference, Digest of Technical Papers, 1992, pp. 131-134.*
W	IEEE Journal of Solid-State Circuits, May 2000, Vol. 35, No. 5, pp. 691-695.

*Mentioned in the Specification

EXAMINER V. Nguyen	DATE CONSIDERED 8/24/09
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